
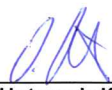


<b>Prüfbericht - Nr.:</b> <i>Test Report No.</i>	<b>50043801 001</b>	Seite <i>Page</i>	1	von <i>of</i>	11
<b>Auftraggeber:</b> <i>Client:</i>	<b>OSAKI ELECTRIC CO., LTD.</b> <b>90-2 Shimodaira, Shizukuishi-cho, Iwate-gun, Iwate, Japan</b>				
<b>Gegenstand der Prüfung:</b> <i>Test item:</i>	<b>DR Device</b>				
<b>Bezeichnung:</b> <i>Identification:</i>	<b>OSAKI_VEN</b>	<b>Serien-Nr.:</b> <i>Serial No.</i>	<b>N/A</b>		
<b>Wareneingangs-Nr.:</b> <i>Receipt No.:</i>	<b>A000386736-001</b>	<b>Eingangsdatum:</b> <i>Date of receipt:</i>	<b>2016-06-28</b>		
<b>Zustand des Prüfgegenstandes bei Anlieferung:</b> <i>Condition of test item at delivery:</i>	<b>Test item complete and undamaged</b>				
<b>Prüfort:</b> <i>Testing location:</i>	<b>TÜV Rheinland Japan Ltd.</b> Head Office Shin Yokohama Daini Center Bldg. 3-19-5 Shin Yokohama, Kohoku-ku, Yokohama 222-0033, Japan				
<b>Prüfgrundlage:</b> <i>Test specification:</i>	<b>OpenADR 2.0b Certification Test Specification v1.1.0</b>				
<b>Prüfergebnis:</b> <i>Test Result:</i>	<b>Der Prüfgegenstand entspricht oben genannter Prüfgrundlage(n).</b> <i>The test item passed the test specification(s).</i>				
<b>Prüflaboratorium:</b> <i>Testing Laboratory:</i>	<b>TÜV Rheinland Japan Ltd.</b> Global Technology Assessment Center 4-25-2 Kita-Yamata, Tsuzuki-ku Yokohama 224-0021, Japan				
<b>geprüft / tested by</b>	<b>kontrolliert / reviewed by:</b>				
<b>2016-06-30, Tam Tran Thanh</b> 	<b>2016-07-05, Olga Kozeruk</b> 				
<b>Datum</b> <i>Date</i>	<b>Unterschrift</b> <i>Signature</i>	<b>Datum</b> <i>Date</i>	<b>Unterschrift</b> <i>Signature</i>		
<b>Sonstiges / Other Aspects:</b>					
Abkürzungen: OK, Pass = entspricht Prüfgrundlage Fail = entspricht nicht Prüfgrundlage N/A = nicht anwendbar					
Abbreviations: OK, Pass = passed Fail = failed N/A = not applicable					
<b>Dieser Prüfbericht bezieht sich nur auf den o.g. Prüfgegenstand und darf ohne Genehmigung der Prüfstelle nicht auszugsweise vervielfältigt werden. Dieser Bericht berechtigt nicht zur Verwendung eines Prüfzeichens.</b> <i>This test report relates to the a. m. test item. Without permission of the test center this test report is not permitted to be duplicated in extracts. This test report does not entitle to carry any test mark on this or similar products.</i>					

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## 1. General Product Information

### 1.1 Client Information

**Company name:** see page 1  
**Address:** see page 1  
**Contact Person:** Kenetsu Tsunokake  
**Phone:** +81-19-692-0132  
**Fax:** N/A  
**Email:** k.tsunokake@osaki.co.jp

### 1.2 General SUT Information

[The system under test is software implementation of OpenADR protocol installed on laptop.]

**Serial number:** N/A  
**Hardware version:** N/A  
**Firmware version:** 1.0

### 1.3 General EUT Description

**Equipment under test:** see page 1

### 1.4 Type of Product

**Product type:** VEN  
**OpenADR profile:** 2.0b  
**Mode:** Pull  
**Transport:** Simple HTTP  
**Security:** Standard Security

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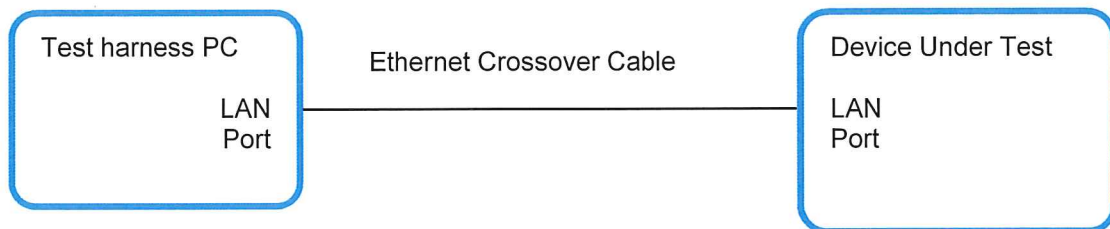
## 2. Testing Laboratory

**Company name:** TÜV Rheinland Japan Ltd.  
**Address:** see page 1

### 2.1 Test Equipment

Instrument	Manufacturer	Model Number	Version/Errata
Test tool	Quality Logic	OpenADR2.0bCertTest	1.1.0

### 2.2 Test Setup



### 2.3 Environmental Conditions

**Temperature:** 19°C to 25°C  
**Relative humidity:** 25% to 75%  
**Testing date:** 2016-06-28 to 29

## 3. Information about Test Results

### 3.1 General

**Documentation of tested devices and results:**

The complete set of measurement results is stored at the TÜV Rheinland Japan Ltd. test laboratory and is available on demand.

**Interpretation of test results:**

The results of the inspection are described on the following pages. "Pass" in the test result list of this test report means the performed test according to the test specification was verified and that the tested device is conformant to the specification. "Fail" means that the performed test according to the test specification was verified and the tested device is not conformant to the specification or that test didn't run to completion because the tested device is not conformant to the specification. "N/A" means the test cases are optional and/or not applicable to the tested device.



## 4. Test Results

### 4.1 VEN Pull Tests

#### 4.1.1 EiRegisterParty Service

No.	Test Case	Date	Result	Log
1	N1_0010_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_103432_252.txt
2	N1_0015_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_104013_917.txt
3	N1_0020_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_103636_424.txt
4	N1_0025_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_104605_171.txt
5	N1_0030_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_104343_403.txt
6	N1_0040_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_105009_939.txt
7	N1_0050_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_105317_692.txt
8	N1_0060_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_105530_829.txt
9	N1_0065_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_105907_239.txt
10	N1_0070_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_110102_825.txt
11	N1_0080_TH_VTN_1	6/28/2016	N/A	TraceLog_062816_110238_705.txt

#### 4.1.2 EiOpt Service

No.	Test Case	Date	Result	Log
1	P1_2010_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_110424_125.txt
2	P1_2015_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_110635_574.txt
3	P1_2020_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_111010_159.txt
4	P1_2030_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_111217_547.txt
5	P1_2040_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_111505_801.txt
6	P1_2050_TH_VTN_1	6/28/2016	N/A	TraceLog_062816_111818_320.txt

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#### 4.1.3 EiReport Service

No.	Test Case	Date	Result	Log
1	R1_3010_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_112158_025.txt
2	R1_3020_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_112416_239.txt
3	R1_3025_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_112807_494.txt
4	R1_3027_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_113251_295.txt
5	R1_3030_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_113915_418.txt
6	R1_3040_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_114341_738.txt
7	R1_3045_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_114608_378.txt
8	R1_3050_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_125915_257.txt
9	R1_3060_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_130255_551.txt
10	R1_3070_TH_VTN_1		SKIP	
11	R1_3080_TH_VTN_1		SKIP	
12	R1_3090_TH_VTN_1		SKIP	
13	R1_3100_TH_VTN_1		SKIP	
14	R1_3120_TH_VTN_1		SKIP	
15	R1_3130_TH_VTN_1		SKIP	
16	R1_3140_TH_VTN_1		SKIP	
17	R1_3150_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_130856_000.txt
18	R1_3160_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_094819_214.txt
19	R1_3170_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_173709_509.txt
20	R1_3180_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_174053_617.txt
21	R1_3190_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_174452_894.txt

#### 4.1.4 EiEvent Service

No.	Test Case	Date	Result	Log
1	E1_1010_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_174841_646.txt
2	E1_1020_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_175000_379.txt
3	E1_1025_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_175231_594.txt
4	E1_1027_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_175400_111.txt
5	E1_1030_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_175537_678.txt
6	E1_1040_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_175743_592.txt
7	E1_1050_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_175958_124.txt
8	E1_1055_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_180230_396.txt
9	E1_1060_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_180421_965.txt
10	E1_1065_TH_VTN_1	6/28/2016	N/A	TraceLog_062816_180701_559.txt
11	E1_1070_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_180725_522.txt
12	E1_1080_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_180943_666.txt
13	E1_1090_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_181150_444.txt

#### 4.1.5 EiEvent Ported A Profile

No.	Test Case	Date	Result	Log
1	A_E1_0020_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_095600_225.txt
2	A_E1_0040_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_095742_584.txt
3	A_E1_0060_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_095905_823.txt
4	A_E1_0070_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_100054_311.txt
5	A_E1_0082_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_100216_750.txt
6	A_E1_0086_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_100404_747.txt
7	A_E1_0090_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_100528_574.txt
8	A_E1_0092_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_100724_941.txt
9	A_E1_0094_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_100917_374.txt
10	A_E1_0096_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_101047_211.txt
11	A_E1_0098_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_101223_086.txt
12	A_E1_0100_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_101353_626.txt
13	A_E1_0102_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_101548_757.txt
14	A_E1_0104_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_101727_421.txt
15	A_E1_0110_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_101857_757.txt
16	A_E1_0130_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_102046_349.txt
17	A_E1_0180_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_102307_868.txt
18	A_E1_0190_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_102639_357.txt
19	A_E1_0200_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_103024_316.txt
20	A_E1_0210_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_110137_336.txt
21	A_E1_0220_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_111115_300.txt
22	A_E1_0230_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_111818_787.txt
23	A_E1_0240_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_112600_802.txt
24	A_E1_0250_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_112930_530.txt
25	A_E1_0260_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_115622_756.txt
26	A_E1_0262_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_121722_093.txt
27	A_E1_0267_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_123628_374.txt
28	A_E1_0268_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_125140_106.txt
29	A_E1_0270_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_113327_561.txt
30	A_E1_0280_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_114144_186.txt
31	A_E1_0285_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_103522_590.txt
32	A_E1_0300_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_103729_805.txt
33	A_E1_0310_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_103853_419.txt
34	A_E1_0340_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_104054_765.txt
35	A_E1_0345_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_104254_222.txt
36	A_E1_0360_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_104555_600.txt
37	A_E1_0370_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_105718_640.txt
38	A_E1_0390_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_104754_190.txt
39	A_E1_0392_TH_VTN_1	6/29/2016	PASS	TraceLog_062916_104938_558.txt



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#### 4.1.6 General Tests

No.	Test Case	Date	Result	Log
1	G1_4005_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_181508_744.txt
2	G1_4007_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_181730_714.txt
3	G1_4010_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_182040_133.txt
4	G1_4015_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_182339_252.txt
5	G1_4030_TH_VTN_1	6/28/2016	PASS	TraceLog_062816_182516_042.txt

## Appendix A: Remarks and References

Log files for the executed test cases are provided in the electronic format.

List of all executed tests with links to the log files is located in the "logfile.xml" which could be opened in any web-browser (Internet Explorer is recommended).

## Appendix B: Photos

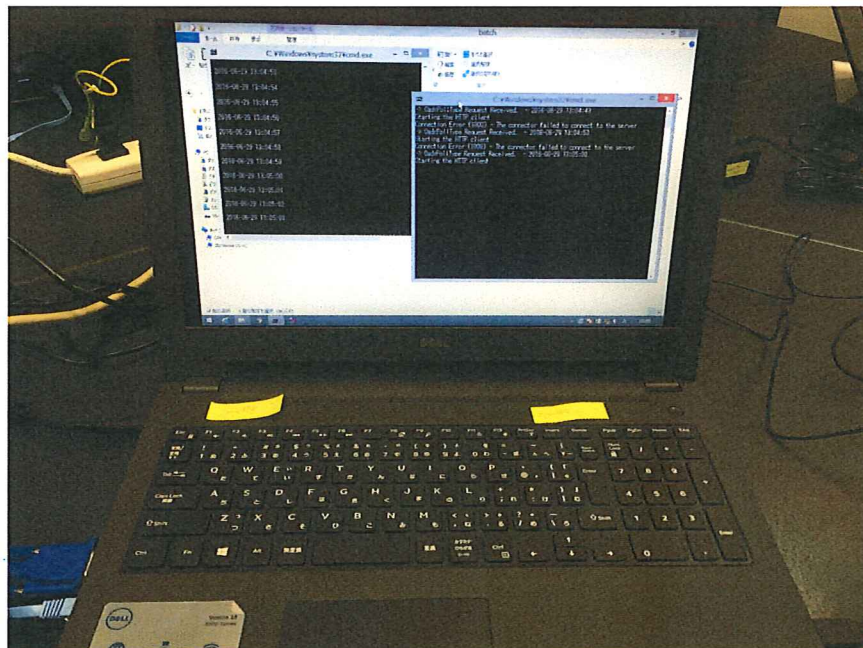


Photo 1: DUT

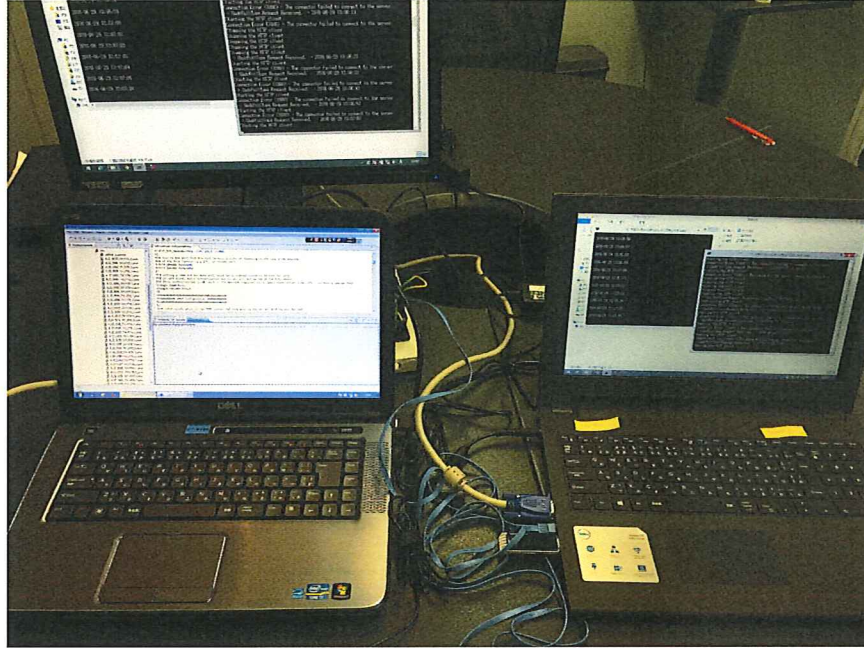


Photo 2: Test Setup